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Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	52
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	24K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 1x12b, 3x16b; D/A 3x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f373rbt6

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Figure 44. LQFP64 P_D max vs. T_A 129

1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32F373xx microcontrollers.

This STM32F373xx datasheet should be read in conjunction with the RM0313 reference manual. The reference manual is available from the STMicroelectronics website www.st.com.

For information on the Cortex[®]-M4 with FPU core, please refer to:

- Cortex[®]-M4 with FPU Technical Reference Manual, available from www.arm.com.
- STM32F3xxx and STM32F4xxx Cortex[®]-M4 programming manual (PM0214) available from www.st.com.



Table 7. STM32F373xx I²C implementation (continued)

I ² C features ⁽¹⁾	I2C1	I2C2
SMBus	X	X
Wakeup from STOP	X	X

1. X = supported.

3.20 Universal synchronous/asynchronous receiver transmitter (USART)

The STM32F373xx embeds three universal synchronous/asynchronous receiver transmitters (USART1, USART2 and USART3).

All USARTs interfaces are able to communicate at speeds of up to 9 Mbit/s.

They provide hardware management of the CTS and RTS signals, they support IrDA SIR ENDEC, the multiprocessor communication mode, the single-wire half-duplex communication mode, Smartcard mode (ISO/IEC 7816 compliant), autobaudrate feature and have LIN Master/Slave capability. The USART interfaces can be served by the DMA controller.

Refer to [Table 8](#) for the features of USART1, USART2 and USART3.

Table 8. STM32F373xx USART implementation

USART modes/features ⁽¹⁾	USART1	USART2	USART3
Hardware flow control for modem	X	X	X
Continuous communication using DMA	X	X	X
Multiprocessor communication	X	X	X
Synchronous mode	X	X	X
Smartcard mode	X	X	X
Single-wire half-duplex communication	X	X	X
IrDA SIR ENDEC block	X	X	X
LIN mode	X	X	X
Dual clock domain and wakeup from Stop mode	X	X	X
Receiver timeout interrupt	X	X	X
Modbus communication	X	X	X
Auto baud rate detection	X	X	X
Driver Enable	X	X	X

1. X = supported.

3.24 Universal serial bus (USB)

The STM32F373xx embeds an USB device peripheral compatible with the USB full-speed 12 Mbs. The USB interface implements a full-speed (12 Mbit/s) function interface. It has software-configurable endpoint setting and suspend/resume support. The dedicated 48 MHz clock is generated from the internal main PLL (the clock source must use a HSE crystal oscillator).

3.25 Serial wire JTAG debug port (SWJ-DP)

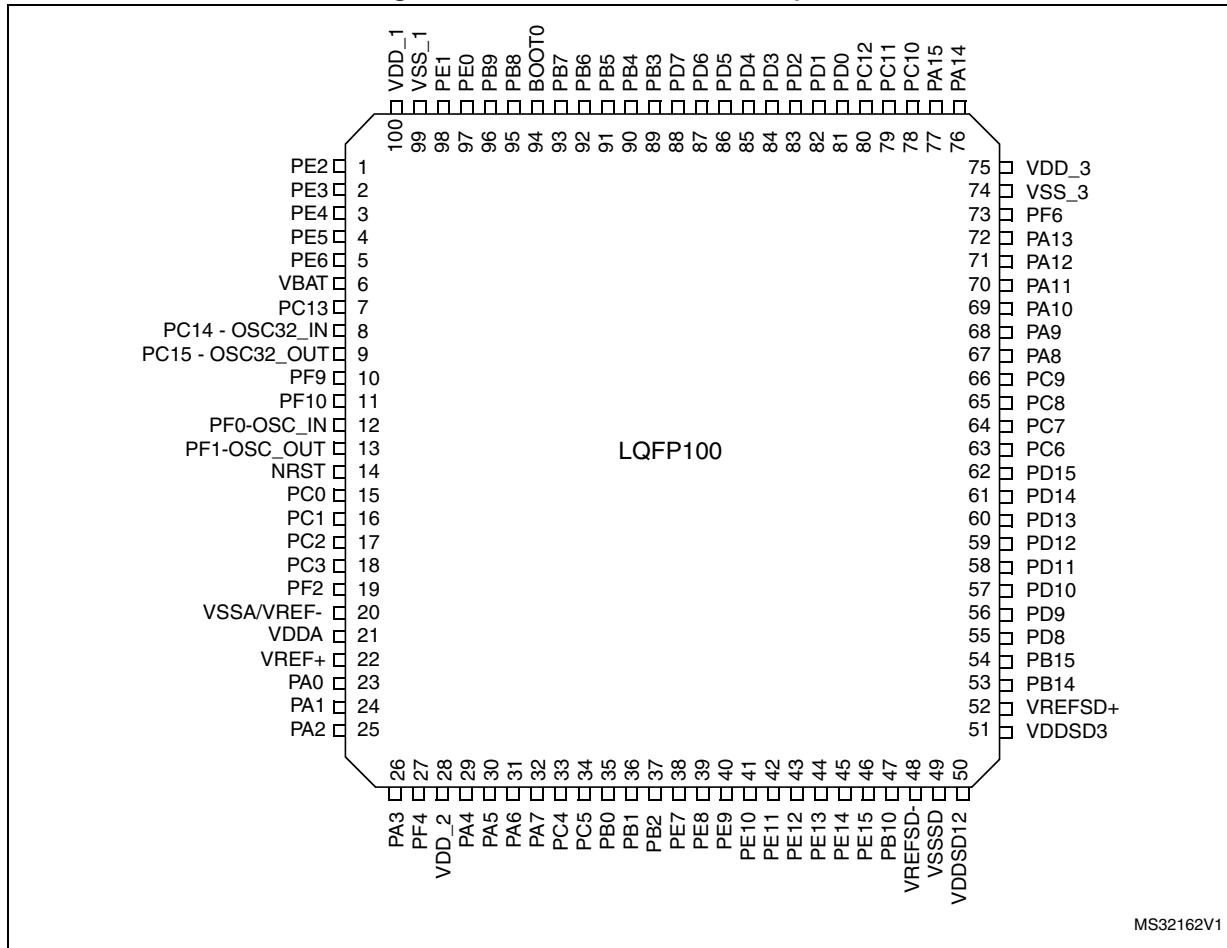
The ARM SWJ-DP Interface is embedded, and is a combined JTAG and serial wire debug port that enables either a serial wire debug or a JTAG probe to be connected to the target.

The JTAG TMS and TCK pins are shared respectively with SWDIO and SWCLK and a specific sequence on the TMS pin is used to switch between JTAG-DP and SW-DP.

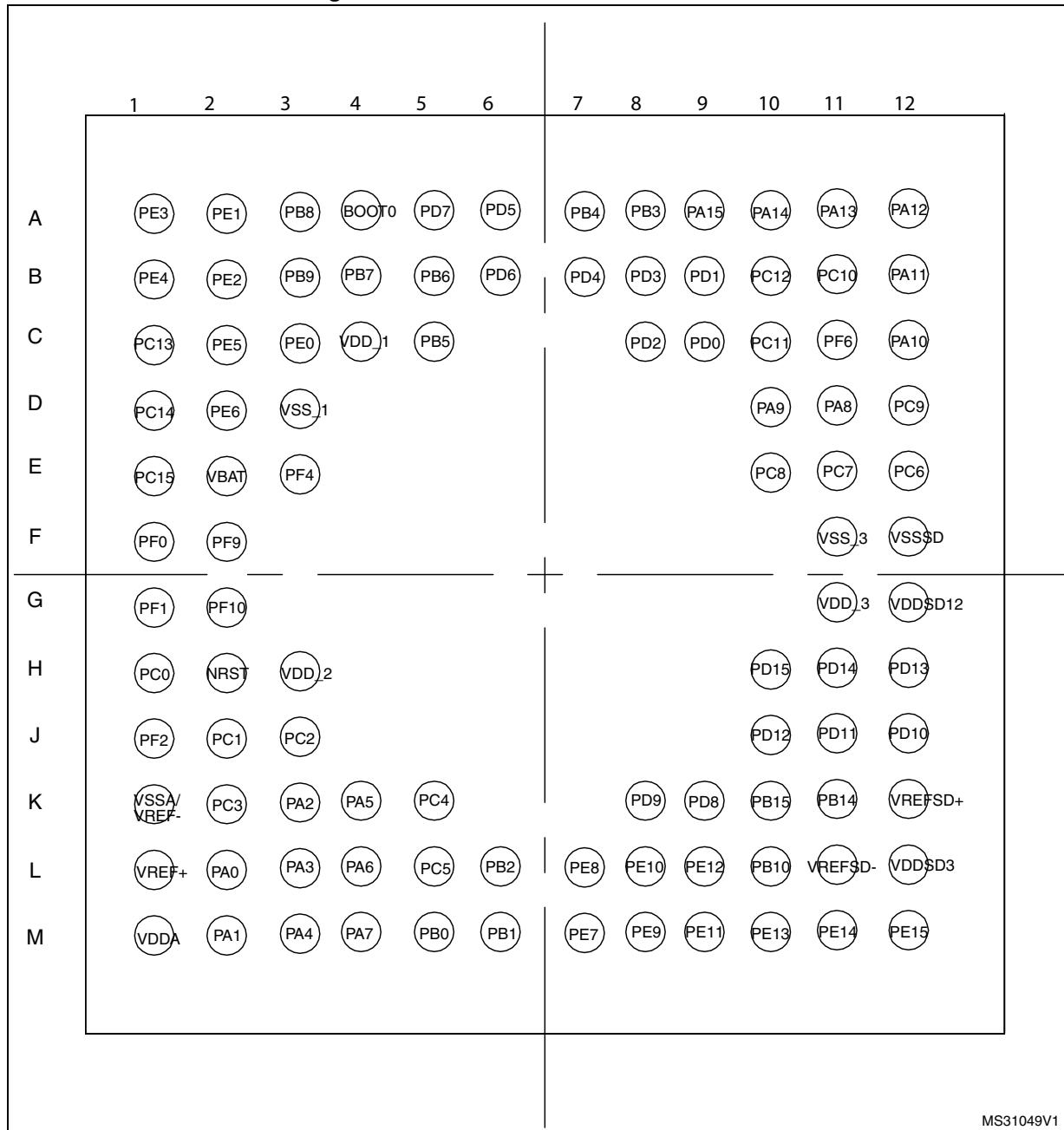
3.26 Embedded trace macrocell™

The ARM embedded trace macrocell provides a greater visibility of the instruction and data flow inside the CPU core by streaming compressed data at a very high rate from the STM32F373xx through a small number of ETM pins to an external hardware trace port analyzer (TPA) device. The TPA is connected to a host computer using USB, Ethernet, or any other high-speed channel. Real-time instruction and data flow activity can be recorded and then formatted for display on the host computer running debugger software. TPA hardware is commercially available from common development tool vendors. It operates with third party debugger software tools.

Figure 4. STM32F373xx LQFP100 pinout



MS32162V1

Figure 5. STM32F373xx UFBGA100 ballout

1. The above figure shows the package top view.

Table 11. STM32F373xx pin definitions (continued)

Pin numbers				Pin name (function after reset)	Pin type	I/O structure	Notes	Pin functions	
LQFP100	UFBGA100	LQFP64	LQFP48					Alternate function	Additional functions
51	L12	-	-	VDDSD3	S	-	(2)	SDADC3 power supply	
52	K12	33	25	VREFSD+	S	-	-	External reference voltage for SDADC1, SDADC2, SDADC3 (positive input)	
53	K11	34	26	PB14	I/O	TC	(4)	SPI2_MISO/I2S2_MCK, USART3_RTS, TIM15_CH1, TIM12_CH1, TSC_G6_IO1	SDADC3_AIN8P
54	K10	35	27	PB15	I/O	TC	(4)	SPI2_MOSI/I2S2_SD, TIM15_CH1N, TIM15_CH2, TIM12_CH2, TSC_G6_IO2, RTC_REFIN	SDADC3_AIN7P, SDADC3_AIN8M
55	K9	36	28	PD8	I/O	TC	(4)	SPI2_SCK/I2S2_CK, USART3_TX, TSC_G6_IO3	SDADC3_AIN6P
56	K8	-	-	PD9	I/O	TC	(4) (2)	USART3_RX, TSC_G6_IO4	SDADC3_AIN5P, SDADC3_AIN6M
57	J12	-	-	PD10	I/O	TC	(4) (2)	USART3_CK	SDADC3_AIN4P
58	J11	-	-	PD11	I/O	TC	(4) (2)	USART3_CTS	SDADC3_AIN3P, SDADC3_AIN4M
59	J10	-	-	PD12	I/O	TC	(4) (2)	USART3_RTS, TIM4_CH1, TSC_G8_IO1	SDADC3_AIN2P
60	H12	-	-	PD13	I/O	TC	(4) (2)	TIM4_CH2, TSC_G8_IO2	SDADC3_AIN1P, SDADC3_AIN2M
61	H11	-	-	PD14	I/O	TC	(4) (2)	TIM4_CH3, TSC_G8_IO3	SDADC3_AIN0P
62	H10	-	-	PD15	I/O	TC	(4) (2)	TIM4_CH4, TSC_G8_IO4	SDADC3_AIN0M
63	E12	37	-	PC6	I/O	FT	(2)	TIM3_CH1, SPI1_NSS/I2S1_WS	-
64	E11	38	-	PC7	I/O	FT	(2)	TIM3_CH2, SPI1_SCK/I2S1_CK,	-
65	E10	39	-	PC8	I/O	FT	(2)	SPI1_MISO/I2S1_MCK, TIM3_CH3	-
66	D12	40	-	PC9	I/O	FT	(2)	SPI1_MOSI/I2S1_SD, TIM3_CH4	-

Table 13. Alternate functions for port PB

Pin Name	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF15
PB0	-	-	TIM3_CH3	TSC_G3_IO3	-	SPI_MOSI/I2S1_SD	-	-	-	-	TIM3_CH2	-	EVENTOUT
PB1	-	-	TIM3_CH4	TSC_G3_IO4	-	-	-	-	-	-	-	-	EVENTOUT
PB2	-	-	-	-	-	-	-	-	-	-	-	-	EVENTOUT
PB3	JTDO-TRACESWO	TIM2_CH2	TIM4_ETR	TSC_G5_IO1	-	SPI1_SCK/I2S1_CK	SPI3_SCK/I2S3_CK	USART2_TX	-	TIM13_CH1	TIM3_ETR	-	EVENTOUT
PB4	NJTRST	TIM16_CH1	TIM3_CH1	TSC_G5_IO2	-	SPI1_MISO/I2S1_MCK	SPI3_MISO/I2S3_MCK	USART2_RX	-	TIM15_CH1N	TIM17_BKIN	-	EVENTOUT
PB5	-	TIM16_BKIN	TIM3_CH2	-	I2C1_SMBA	SPI1_MOSI/I2S1_SD	SPI3_MOSI/I2S3_SD	USART2_CK	-	-	TIM17_CH1	TIM19_ETR	EVENTOUT
PB6	-	TIM16_CH1N	TIM4_CH1	TSC_G5_IO3	I2C1_SCL	-	-	USART1_TX	-	TIM15_CH1	TIM3_CH3	TIM19_CH1	EVENTOUT
PB7	-	TIM17_CH1N	TIM4_CH2	TSC_G5_IO4	I2C1_SDA	-	-	USART1_RX	-	TIM15_CH2	TIM3_CH4	TIM19_CH2	EVENTOUT
PB8	-	TIM16_CH1	TIM4_CH3	TSC_SYNC	I2C1_SCL	SPI2_SCK/I2S2_CK	CEC	USART3_TX	COMP1_OUT	CAN_RX	-	TIM19_CH3	EVENTOUT
PB9	-	TIM17_CH1	TIM4_CH4	-	I2C1_SDA	SPI2_NSS/I2S2_WS	IR-OUT	USART3_RX	COMP2_OUT	CAN_TX	-	TIM19_CH4	EVENTOUT
PB10	-	TIM2_CH3	-	TSC_SYNCH	-	SPI2_SCK/I2S2_CK	CEC	USART3_TX	-	-	-	-	EVENTOUT
PB14	-	TIM15_CH1	-	TSC_G6_IO1	-	SPI2_MISO/I2S2_MCK	-	USART3_RTS	-	TIM12_CH1	-	-	EVENTOUT
PB15	RTC_REFIN	TIM15_CH2	TIM15_CH1N	TSC_G6_IO2	-	SPI2_MOSI/I2S2_SD	-	-	-	TIM12_CH2	-	-	EVENTOUT

Table 15. Alternate functions for port PD

Pin Name	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
PD0	-	EVENTOUT	TIM19_CH4	-	-	-	-	CAN_RX
PD1	-	EVENTOUT	TIM19_ETR	-	-	-	-	CAN_TX
PD2	-	EVENTOUT	TIM3_ETR	-	-	-	-	-
PD3	-	EVENTOUT	-	-	-	SPI2_MISO/I2S2_MCK	-	USART2_CTS
PD4	-	EVENTOUT	-	-	-	SPI2_MOSI/I2S2_SD	-	USART2_RTS
PD5	-	EVENTOUT	-	-	-	-	-	USART2_TX
PD6	-	EVENTOUT	-	-	-	SPI2_NSS/I2S2_WS	-	USART2_RX
PD7	-	EVENTOUT	-	-	-	SPI2_SCK/I2S2_CK	-	USART2_CK
PD8	-	EVENTOUT	-	TSC_G6_IO3	-	SPI2_SCK/I2S2_CK	-	USART3_TX
PD9	-	EVENTOUT	-	TSC_G6_IO4	-	-	-	USART3_RX
PD10	-	EVENTOUT	-	-	-	-	-	USART3_CK
PD11	-	EVENTOUT	-	-	-	-	-	USART3_CTS
PD12	-	EVENTOUT	TIM4_CH1	TSC_G8_IO1	-	-	-	USART3_RTS
PD13	-	EVENTOUT	TIM4_CH2	TSC_G8_IO2	-	-	-	-
PD14	-	EVENTOUT	TIM4_CH3	TSC_G8_IO3	-	-	-	-
PD15	-	EVENTOUT	TIM4_CH4	TSC_G8_IO4	-	-	-	-

Table 34. Typical current consumption in Sleep mode, code running from Flash or RAM

Symbol	Parameter	Conditions	f_{HCLK}	Typ		Unit
				Peripherals enabled	Peripherals disabled	
I_{DD}	Supply current in Sleep mode from V_{DD} supply	Running from HSE crystal clock 8 MHz, code executing from Flash or RAM, PLL on	72 MHz	42.8	6.9	mA
			64 MHz	38.2	6.2	
			48 MHz	28.9	4.8	
			32 MHz	19.5	3.4	
			24 MHz	14.7	2.7	
			16 MHz	10.2	2.0	
		Running from HSE crystal clock 8 MHz, code executing from Flash or RAM, PLL off	8 MHz	5.2	1.2	
			4 MHz	3.4	1.1	
			2 MHz	2.2	0.9	
			1 MHz	1.6	0.9	
			500 kHz	1.4	0.8	
			125 kHz	1.1	0.8	
$I_{DDA}^{(1)}$	Supply current in Sleep mode from V_{DDA} supply	Running from HSE crystal clock 8 MHz, code executing from Flash or RAM, PLL on	72 MHz	242.9	241.5	μA
			64 MHz	213.7	212.7	
			48 MHz	158.8	158.0	
			32 MHz	107.6	107.3	
			24 MHz	82.7	82.6	
			16 MHz	58.3	58.2	
		Running from HSE crystal clock 8 MHz, code executing from Flash or RAM, PLL off	8 MHz	1.2	1.2	
			4 MHz	1.2	1.2	
			2 MHz	1.2	1.2	
			1 MHz	1.2	1.2	
			500 kHz	1.2	1.2	
			125 kHz	1.2	1.2	

1. V_{DDA} monitoring is off, V_{DDSD12} monitoring is off.

Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latch-up standard.

Table 50. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	$T_A = +105^\circ\text{C}$ conforming to JESD78A	II level A

6.3.13 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard, 3 V-capable I/O pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (higher than 5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of $-5 \mu\text{A}/+0 \mu\text{A}$ range), or other functional failure (for example reset occurrence or oscillator frequency deviation).

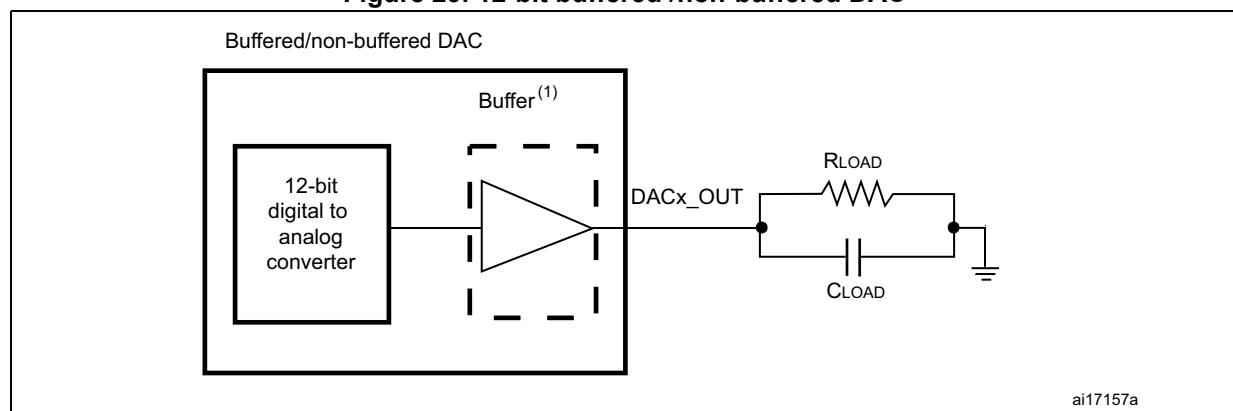
The test results are given in [Table 51](#).

Table 63. DAC characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Offset ⁽³⁾	Offset error (difference between measured value at Code (0x800) and the ideal value = $V_{REF+}/2$)	-	-	-	± 10	mV
		Given for the DAC in 10-bit at $V_{REF+} = 3.6$ V	-	-	± 3	LSB
		Given for the DAC in 12-bit at $V_{REF+} = 3.6$ V	-	-	± 12	LSB
Gain error ⁽³⁾	Gain error	Given for the DAC in 12bit configuration	-	-	± 0.5	%
t _{SETTLING} ⁽³⁾	Settling time (full scale: for a 10-bit input code transition between the lowest and the highest input codes when DAC_OUT reaches final value ± 1 LSB)	$C_{LOAD} \leq 50$ pF, $R_{LOAD} \geq 5$ k Ω	-	3	4	μ s
Update rate ⁽³⁾	Max frequency for a correct DAC_OUT change when small variation in the input code (from code i to i+1LSB)	$C_{LOAD} \leq 50$ pF, $R_{LOAD} \geq 5$ k Ω	-	-	1	MS/s
t _{WAKEUP} ⁽³⁾	Wakeup time from off state (Setting the ENx bit in the DAC Control register)	$C_{LOAD} \leq 50$ pF, $R_{LOAD} \geq 5$ k Ω input code between lowest and highest possible ones.	-	6.5	10	μ s
PSRR+ ⁽¹⁾	Power supply rejection ratio (to V_{DDA}) (static DC measurement	No R_{LOAD} , $C_{LOAD} = 50$ pF	-	-67	-40	dB

1. Guaranteed by design.
2. Quiescent mode refers to the state of the DAC keeping a steady value on the output, so no dynamic consumption is involved.
3. Guaranteed by characterization.

Figure 29. 12-bit buffered /non-buffered DAC



1. The DAC integrates an output buffer that can be used to reduce the output impedance and to drive external loads directly without the use of an external operational amplifier. The buffer can be bypassed by configuring the BOFFx bit in the DAC_CR register.

Table 74. SDADC characteristics (continued)⁽¹⁾

Symbol	Parameter	Conditions			Min	Typ	Max	Unit	Note				
EO	Offset error	Differential mode	gain = 1	f _{ADC} = 1.5 MHz	V _{DDSDx} = 3.3	V _{REFSD+} = 3.3	-	-	110	uV after offset calibration			
				f _{ADC} = 6 MHz		V _{REFSD+} = 1.2	-	-	110				
			gain = 8	f _{ADC} = 6 MHz		V _{REFSD+} = 3.3	-	-	100				
				f _{ADC} = 1.5 MHz		V _{REFSD+} = 1.2	-	-	70				
		Single ended mode	gain = 1	-		V _{REFSD+} = 3.3	-	-	100				
						V _{REFSD+} = 3.3	-	-	90				
			gain = 8			V _{REFSD+} = 1.2	-	-	2100				
						V _{REFSD+} = 3.3	-	-	2000				
			gain = 1			V _{REFSD+} = 1.2	-	-	1500				
						V _{REFSD+} = 3.3	-	-	1800				
D _{voffsettemp}	Offset drift with temperature	Differential or single ended mode, gain = 1, V _{DDSDx} = 3.3 V			-	10	15	uV/K	-				
EG	Gain error	All gains, differential mode, single ended mode			-2.4	-2.7	-3.1	%	negative gain error = data result are greater than ideal				
EGT	Gain drift with temperature	gain = 1, differential mode, single ended mode			-	0	-	ppm/K	-				

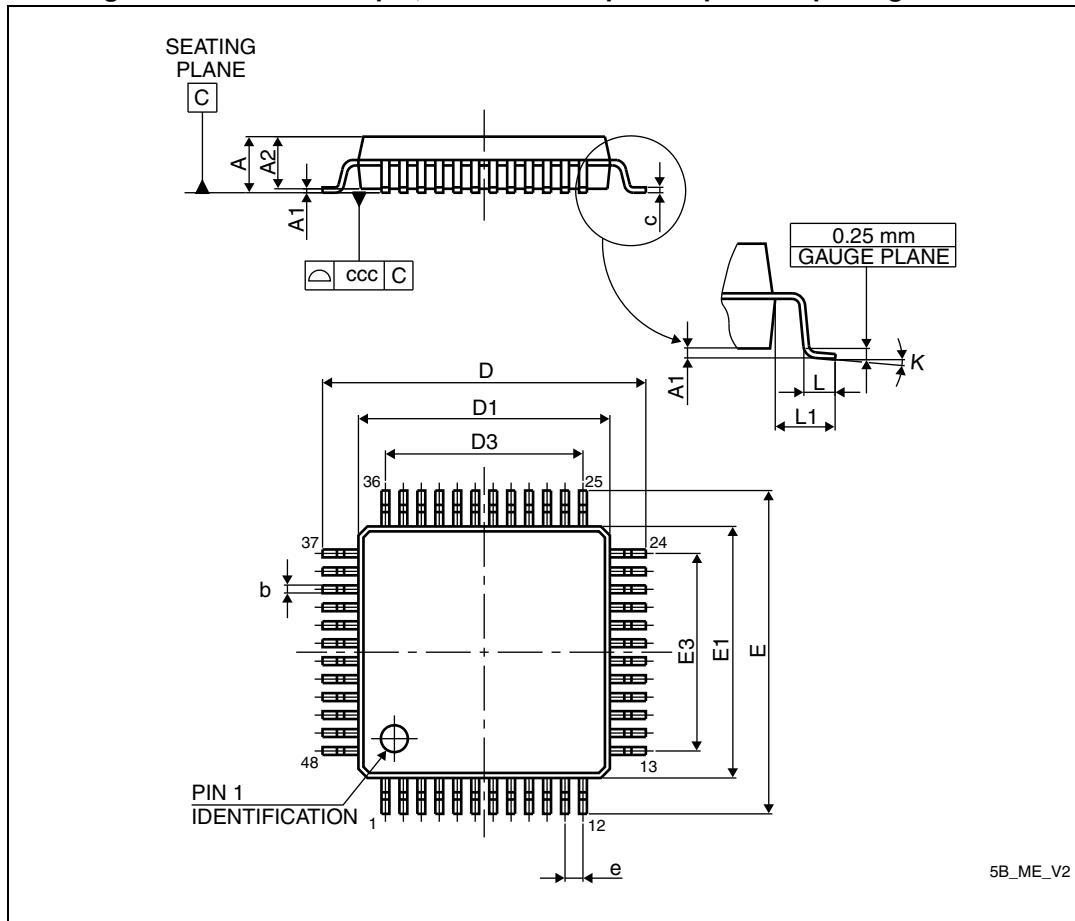
Table 79. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
K	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

7.4 LQFP48 package information

Figure 41. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline



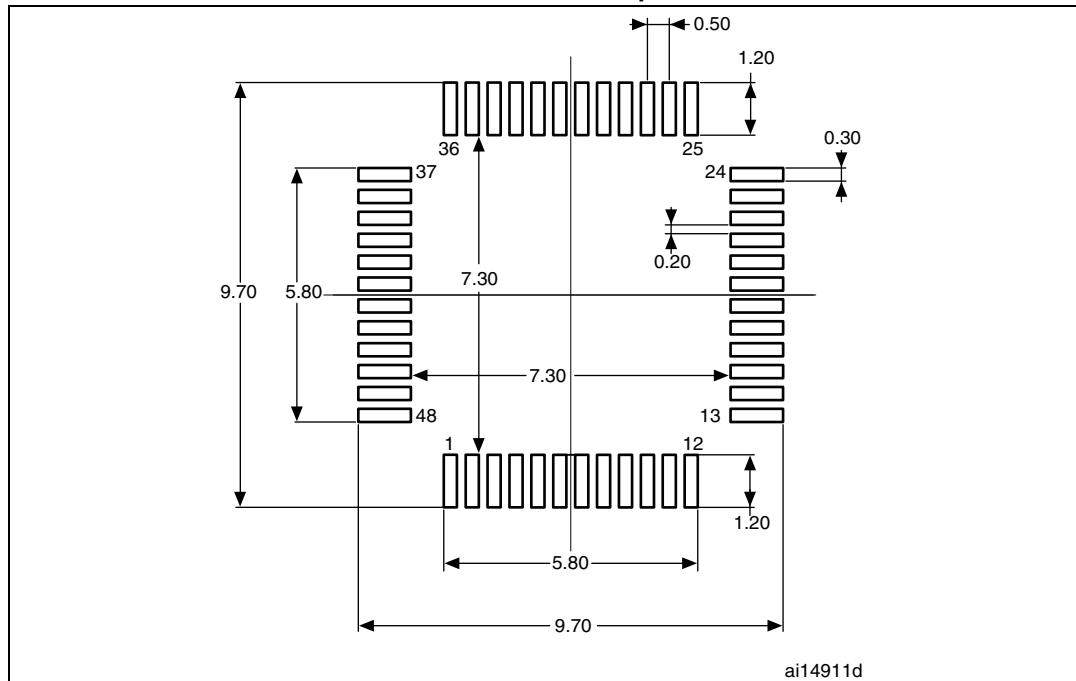
1. Drawing is not to scale.

**Table 80. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package
mechanical data**

Symbol	millimeters			inches⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.500	-	-	0.2165	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.500	-	-	0.2165	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 42. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package recommended footprint

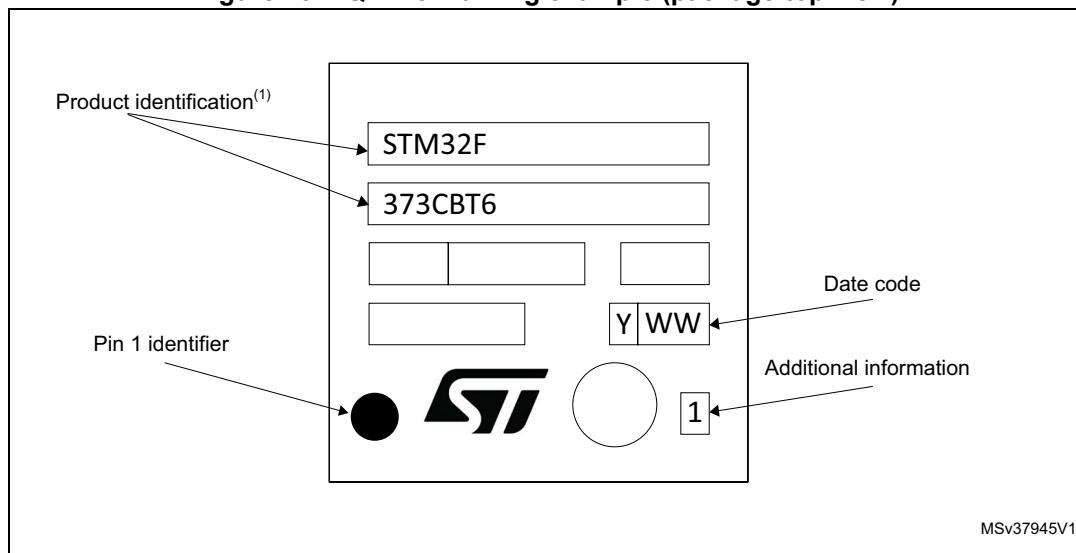


1. Dimensions are expressed in millimeters.

Device marking for LQFP48

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 43. LQFP48 marking example (package top view)



1. Samples marked "ES" are to be considered as "Engineering Samples": i.e. they are intended to be sent to customer for electrical compatibility evaluation and may be used to start customer qualification where specifically authorized by ST in writing. In no event ST will be liable for any customer usage in production. Only if ST has authorized in writing the customer qualification Engineering Samples can be used for reliability qualification trials.

8 Part numbering

For a list of available options (memory, package, and so on) or for further information on any aspect of this device, please contact your nearest ST sales office.

Table 82. Ordering information scheme

Example:	STM32	F	373	R	8	T	6	x
Device family								
STM32 = ARM-based 32-bit microcontroller								
Product type								
F = General-purpose								
Sub-family								
373 = STM32F373xx								
Pin count								
C = 48 pins								
R = 64 pins								
V = 100 pins								
Code size								
8 = 64 Kbytes of Flash memory								
B = 128 Kbytes of Flash memory								
C = 256 Kbytes of Flash memory								
Package								
T = LQFP								
H = BGA								
Temperature range								
6 = Industrial temperature range, -40 to 85 °C								
7 = Industrial temperature range, -40 to 105 °C								
Options								
xxx = programmed parts								
TR = tape and reel								

9 Revision history

Table 83. Document revision history

Date	Revision	Changes
18-Jun-2012	1	<p>Initial release.</p>
07-Sep-2012	2	<p>Added 'F' to all 'Cortex-M4' occurrences</p> <p>Modified the shapes of <i>Figure 2: STM32F373xx LQFP48 pinout</i> to <i>Figure 4: STM32F373xx LQFP100 pinout</i></p> <p>Added two rows 'VREFSD+ - VDDSD3' and 'VREF+ - VDDA' in <i>Table 19: Voltage characteristics</i></p> <p>Removed PB0 in footnote of <i>Table 19: Voltage characteristics</i> and in <i>Section 6.3.14: I/O port characteristics</i></p> <p>Added a paragraph after '...power up sequence' in <i>Section 6.2: Absolute maximum ratings</i> and after '...in output mode' in <i>I/O system current consumption</i></p> <p>Corrected SDAC_VREF+ in <i>Figure 9: Power supply scheme</i></p> <p>Modified <i>Table 20: Current characteristics</i></p> <p>Added BGA100 in <i>Table 22: General operating conditions</i></p> <p>Added values in <i>Table 27: Embedded internal reference voltage</i></p> <p>Filled values in <i>Table 28: Typical and maximum current consumption from VDD supply at VDD = 3.6 V</i></p> <p>Filled values in <i>Table 29: Typical and maximum current consumption from VDDA supply</i></p> <p>Filled values in <i>Table 30: Typical and maximum VDD consumption in Stop and Standby modes</i></p> <p>Removed table: "Typical and maximum VDDA consumption in Stop modes"</p> <p>Filled values in <i>Table 31: Typical and maximum VDDA consumption in Stop and Standby modes</i></p> <p>Added VBAT values in <i>Table 32: Typical and maximum current consumption from VBAT supply</i></p> <p>Added typ values in <i>Table 33: Typical current consumption in Run mode, code with data processing running from Flash</i> and <i>Table 34: Typical current consumption in Sleep mode, code running from Flash or RAM</i></p> <p>Added max value in <i>Table 41: LSE oscillator characteristics (fLSE = 32.768 kHz)</i></p> <p>Modified min and max values in <i>Table 42: HSI oscillator characteristics</i></p> <p>Added values in <i>Table 37: Low-power mode wakeup timings</i></p> <p>Added Class values in <i>Table 47: EMS characteristics</i></p> <p>Modified values in <i>Table 48: EMI characteristics</i></p> <p>Added values in <i>Table 49: ESD absolute maximum ratings</i></p> <p>Added class value in <i>Table 50: Electrical sensitivities</i></p> <p>Modified values and descriptions in <i>Table 51: I/O current injection susceptibility</i></p>